

USB3.1, USB3.0 and USB2.0 Combo Switch

Features

- 1:2 mux/demux for USB 3.1 Enhanced SS, USB 3.0 SS, 2.0HS, and 2.0FS signals
- Switches Tx, Rx, and Dx from USB3.0 connector
- Suitable for DisplayPort, PCIe Gen1/2/3, SATA 1.5/3/6G, SAS 1.5/3/6G and XAUI applications.
- -3dB bandwidth for enhanced superspeed channel: 10.6GHz
- Insertion Loss for enhanced superspeed channels @ 5.0 GHz: -1.5dB
- Insertion Loss for superspeed channels @ 2.5 GHz: -0.9dB
- Return loss for enhanced superspeed channels @ 5.0 GHz: -19.6dB
- Return Loss for superspeed channels @ 2.5 GHz: -26.4dB
- Low Bit-to-Bit Skew, 5ps typ(between '+' and '-' bits)
- Low Crosstalk for enhanced superspeed channels: -31.1dB @ 5.0 GHz
- Low Crosstalk for superspeed channels @2.5GHz: -33.3dB
- Low Off Isolation for enhanced superspeed channels: -17.4dB @ 5.0 GHz
- Low Off Isolation for superspeed channels @ 2.5GHz: -24.9dB
- Insertion Loss for USB – HS: -0.67dB @ 480Mbps
- Crosstalk for USB – HS: -33dB @ 480Mbps
- Off Isolation fo USB – HS: -30dB @ 480Mbps
- -3dB for USB – HS: 1.4 GHz
- V_{DD} Operating Range: 3.3V +/-10%
- ESD Tolerance: 2kV HBM
- Low channel-to-channel skew, 7ps typ
- Packaging (Pb-free & Green):
 - 32 TQFN (ZL) 3mm x 6mm x 0.75mm, 0.4mm pitch

Description

The PI3USB32212 USB3.1, USB3.0 and USB2.0 Combo Switch is a complete 1:2 switching solution for Enhanced SuperSpeed USB 3.1 signals. PI3USB32122 provides differential high-speed lanes for the USB3.1 10Gbps, USB3.0 5Gbps TX and RX lanes as well as a differential lane for 480 Mbps USB 2.0 signals.

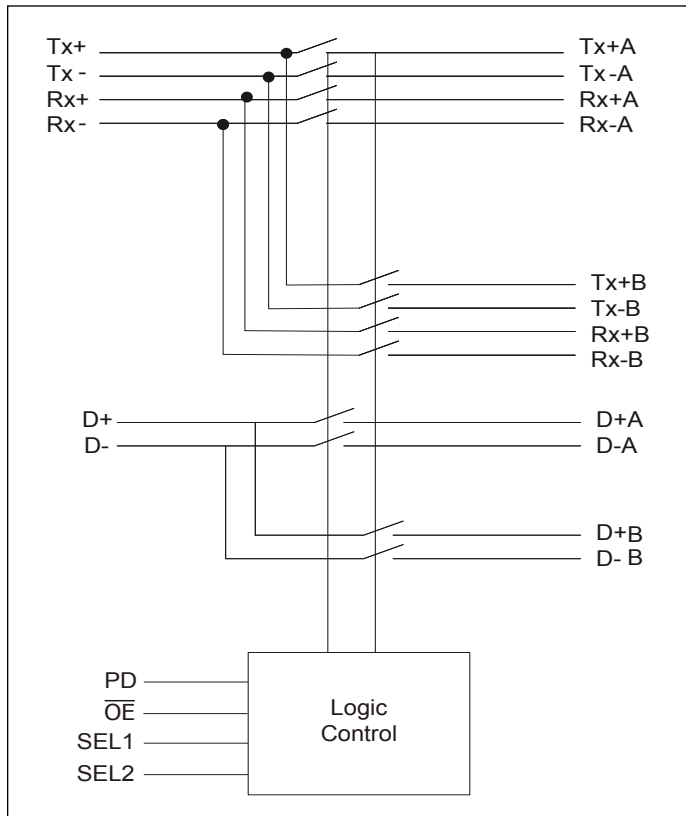
PI3USB32212 can be used to connect two hosts to a single device or a single host to two devices.

PI3USB32212 offers excellent signal integrity for high-speed signals and low power dissipation. Insertion loss is -1.3dB and return loss is -19dB at 5 GHz (USB3.1). Insertion loss is -0.77dB and return loss is -27.8db at 2.5GHz (USB3.0).

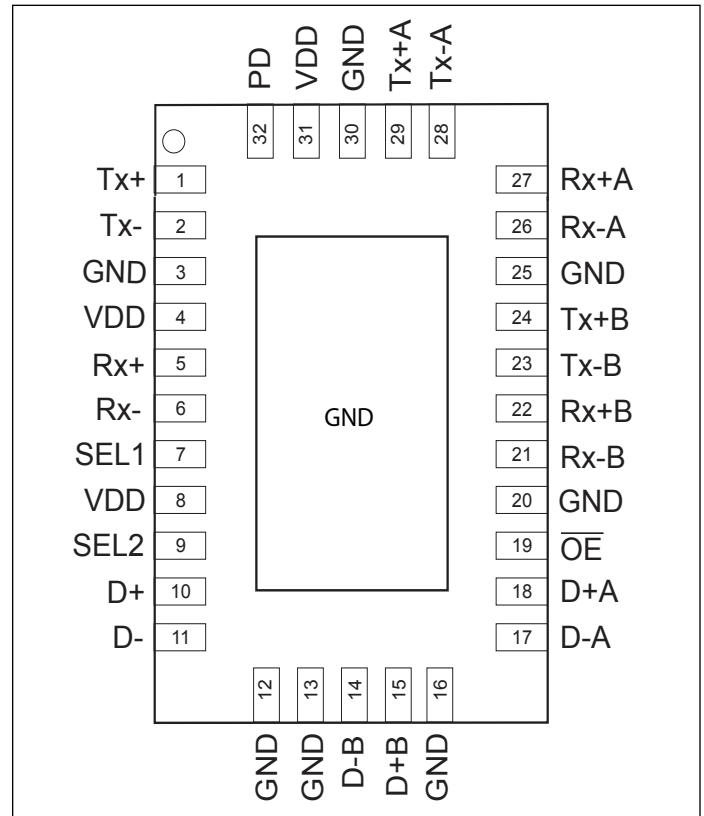
Application

Routing of USB3.1/3.0/2.0 signals with low signal attenuation between source and sink. Applicable products include desktop PC, Notebook PC, Tablet, Docking, Telecom, DTV.

Block Diagram



Pin Assignment (TQFN-32)



Truth Table

| PD | \overline{OE} | SEL1 | SEL2 | Function |
|----|-----------------|------|------|---------------------------------|
| 0 | X | 0 | X | PortA is active for Tx & Rx |
| 0 | X | 1 | X | PortB is active for Tx & Rx |
| 1 | X | X | X | Both ports are Hi_Z for Tx & Rx |
| X | 1 | X | X | Both ports are High_Z for D+/D- |
| 1 | 1 | X | X | All channels are High_Z |
| X | 0 | X | 0 | PortB is active for D+/D- |
| X | 0 | X | 1 | PortA is active for D+/D- |

Note:

1. PD & SEL1 are controls for the usb3.1 switch PD supports power down & output disable
2. \overline{OE} & SEL2 are controls for the usb2.0 switch
3. Bottom metal plate can be used as GND
4. VDD at pin8 provides power to both top and bottom die
5. All VDD need to connect to power

Pin Description

| Pin# | Pin Name | Signal Type | Description |
|------|-----------------|-------------|---|
| 1 | Tx+ | I/O | Positive differential USB3.x Tx signal for COM port |
| 2 | Tx- | I/O | Negative differential USB3.x Tx signal for COM port |
| 3 | GND | Ground | Ground |
| 4 | VDD | Power | 3.3V +/-10% power supply |
| 5 | Rx+ | I/O | Positive differential USB3.x Rx signal for COM port |
| 6 | Rx- | I/O | Negative differential USB3.x Rx signal for COM port |
| 7 | SEL1 | I | Control for USB 3.x |
| 8 | VDD | Power | 3.3V +/-10% power supply |
| 9 | SEL2 | I | Control for USB 2.0 |
| 10 | D+ | I/O | Positive differential USB 2.0 COM port |
| 11 | D- | I/O | Negative differential USB2.0 COM port |
| 12 | GND | Ground | Ground |
| 13 | GND | Ground | Ground |
| 14 | D-B | I/O | Negative differential USB2.0 signal for port 1 |
| 15 | D+B | I/O | Positive differential USB2.0 signal for port 1 |
| 16 | GND | Ground | Ground |
| 17 | D-A | I/O | Negative differential USB2.0 signal for port 0 |
| 18 | D+A | I/O | Positive differential USB2.0 signal for port 0 |
| 19 | \overline{OE} | I | Control for USB 2.0 |
| 20 | GND | Ground | Ground |
| 21 | Rx-B | I/O | Negative differential USB 3.x signal for port 0 |
| 22 | Rx+B | I/O | Positive differential USB 3.x signal for port 0 |
| 23 | Tx-B | I/O | Negative differential USB3.x Rx signal for port 0 |
| 24 | Tx+B | I/O | Positive differential USB3.x Tx signal for port 0 |
| 25 | GND | Ground | Ground |
| 26 | Rx-A | I/O | Negative differential USB3.xRx signal for port 1 |
| 27 | Rx+A | I/O | Positive differential USB3.x Rx signal for port 1 |
| 28 | Tx-A | I/O | Negative differential USB3.x Rx signal for port 1 |
| 29 | Tx+A | I/O | Positive differential USB3.x Tx signal for port 1 |
| 30 | GND | Ground | Ground |
| 31 | VDD | Power | 3.3V +/-10% power supply |
| 32 | PD | I | Power down and disable USB3.x output |

Maximum Ratings

(Above which useful life may be impaired. For user guidelines, not tested.)

| | |
|--|--------------------------|
| Storage Temperature | -65°C to +150°C |
| Supply Voltage to Ground Potential | -0.5V to +4.0V |
| DC Input Voltage, USB3 | -0.5V to 1.5V |
| DC Input Voltage, USB2 | -0.5V to V _{DD} |
| DC Output Current | 120mA |
| Power Dissipation | 0.5W |
| ESD..... | 2KV HBM |

Note: Stresses greater than those listed under MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

DC Electrical Characteristics for Switching over Operating Range

(T_A = -40°C to +85°C, V_{DD} = 3.3V ±10%)

| Parameter | Description | Test Conditions ⁽¹⁾ | Min. | Typ. ⁽¹⁾ | Max. | Units |
|--------------------|---|--|----------------------|---------------------|------|-------|
| V _{IH} | Input HIGH Voltage | Guaranteed HIGH level | 0.65*V _{DD} | | | V |
| V _{IL} | Input LOW Voltage | Guaranteed LOW level | | | 0.6 | |
| V _{IK} | Clamp Diode Voltage, Dx | V _{DD} = Max., I _{IN} = -18mA | | -0.7 | -1.2 | |
| I _{IH} | Input HIGH Current | V _{DD} = Max., V _{IN} = V _{DD} | | | ±5 | µA |
| I _{IL} | Input LOW Current | V _{DD} = Max., V _{IN} = GND | | | ±5 | |
| R _{ON_SS} | On resistance between input to output for SuperSpeed signals | V _{DD} = 3.3V, V _{input} = 0V to 1V, I _{INPUT} = 20mA | | 10 | 13 | Ohm |
| R _{ON_FS} | On resistance between input to output for USB2.0 FS signals (D+/D-) | V _{DD} = 3.3V, V _{input} = 0 to 3.3V, I _{INPUT} = 20mA | | 7 | 9 | Ohm |
| R _{ON_HS} | On resistance between input to output for USB2.0 HS signals (D+/D-) | V _{DD} = 3.3V, V _{input} = -0.4V to +0.4V, I _{INPUT} = 20mA | | 4 | 6 | Ohm |

Power Supply Characteristics (T_A = -40°C to +85°C)

| Parameter | Description | Test Conditions ⁽¹⁾ | Min. | Typ. ⁽¹⁾ | Max. | Units |
|-----------------|--------------------------------|--|------|---------------------|------|-------|
| I _{CC} | Quiescent Power Supply Current | V _{DD} = Max., V _{IN} = GND or V _{DD} | | | 500 | µA |

Dynamic Electrical Characteristics over Operating Range ($T_A = -40^\circ$ to $+85^\circ\text{C}$, $V_{DD} = 3.3\text{V} \pm 10\%$)

| Parameter | Description | Test Conditions | | Min. | Typ. | Max. | Units |
|---------------------------|--|-----------------------------------|----------------------|------|-------|------|-------|
| DDXT | Differential Crosstalk on SuperSpeed Channels | See Fig. 1 for Measurement Setup | $f = 2.5\text{ GHz}$ | | -33.3 | | dB |
| | | | $f = 4.0\text{ GHz}$ | | -31.9 | | |
| | | | $f = 5.0\text{ GHz}$ | | -31.1 | | |
| DDOI | Differential OFF Isolation on SuperSpeed Channels | See Fig. 2 for Measurement Setup, | $f = 2.5\text{ GHz}$ | | -24.9 | | |
| | | | $f = 4.0\text{ GHz}$ | | -18.9 | | |
| | | | $f = 5.0\text{ GHz}$ | | -17.4 | | |
| DDIL | Differential Insertion Loss on SuperSpeed Channels | $f = 2.5\text{ GHz}$ | | | -0.9 | | dB |
| | | $f = 4.0\text{ GHz}$ | | | -1.3 | | |
| | | $f = 5.0\text{ GHz}$ | | | -1.5 | | |
| R_{loss} | Differential Return Loss on SuperSpeed channels | $f = 2.5\text{ GHz}$ | | | -26.4 | | dB |
| | | $f = 4.0\text{ GHz}$ | | | -22.4 | | |
| | | $f = 5.0\text{ GHz}$ | | | -19.6 | | |
| BW | 3db Bandwidth on SuperSpeed channels | | | | 10.6 | | GHz |
| $X_{\text{TALK-USB2 HS}}$ | Crosstalk | $R_L = 50\Omega$ | $f = 240\text{ MHz}$ | -35 | -39 | | dB |
| | | | $f = 825\text{ MHz}$ | -25 | -28 | | |
| $O_{\text{IRR-USB2 HS}}$ | OFF Isolation | | $f = 240\text{ MHz}$ | -29 | -32 | | |
| | | | $f = 825\text{ MHz}$ | -20 | -23 | | |
| $BW_{\text{-USB2 HS}}$ | -3dB Bandwidth | $R_L = 50\Omega$ | | 1100 | 1400 | | MHz |
| $BW_{\text{-USB2 HS}}$ | -0.5dB Bandwidth | $R_L = 50\Omega$ | | 150 | 400 | | MHz |
| $IN_{\text{-USB2 HS}}$ | Insertion Loss | $f = 240\text{ MHz}$ | | | 0.47 | 0.67 | dB |
| | | $f = 825\text{ MHz}$ | | | 1.8 | 2.4 | |
| | | $f = 1.0\text{ GHz}$ | | | 2.2 | 2.6 | |
| | | $f = 1.125\text{ GHz}$ | | | 2.4 | 3.0 | |

Note:

- For Max. or Min. conditions, use appropriate value specified under Electrical Characteristics for the applicable device type.
- Typical values are at $V_{DD} = 3.3\text{V}$, $T_A = 25^\circ\text{C}$ ambient and maximum loading.

Switching Characteristics ($T_A = -40^\circ$ to $+85^\circ\text{C}$, $V_{DD} = 3.3\text{V} \pm 10\%$)

| Parameter | Description | Min. | Typ. | Max. | Units |
|--------------------|--|--------|------|------|-------|
| T_{pd} | Propagation delay (input pin to output pin) | USB3 | 80 | | ps |
| | | USB-HS | 250 | | |
| $t_{\text{b-b}}$ | Bit-to-bit skew within the same differential pair | | | 10 | ps |
| $t_{\text{ch-ch}}$ | Channel-to-channel skew | | | 20 | ps |
| T_{sw} | Switching time between paths (toggling SEL1, SEL2) | 2 | | 100 | ns |

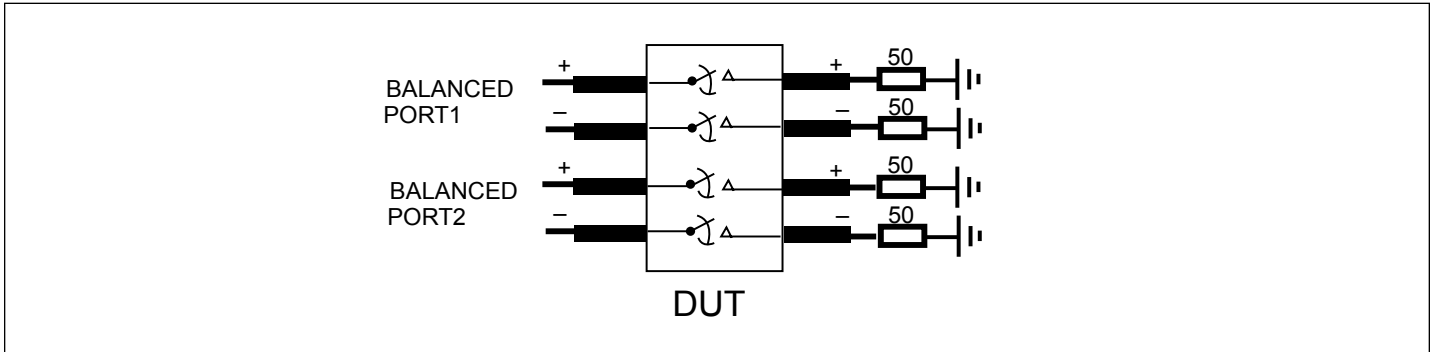


Fig 1. Crosstalk Setup

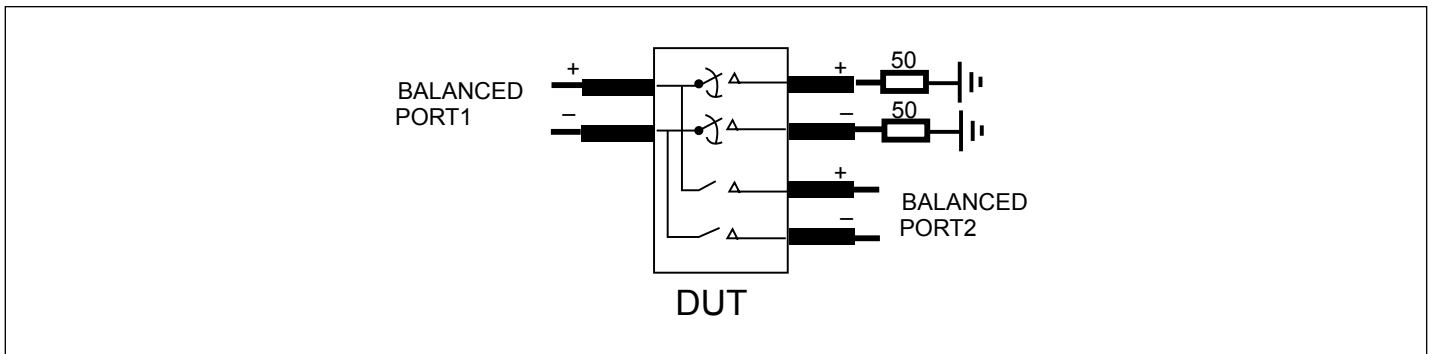


Fig 2. Off-isolation setup

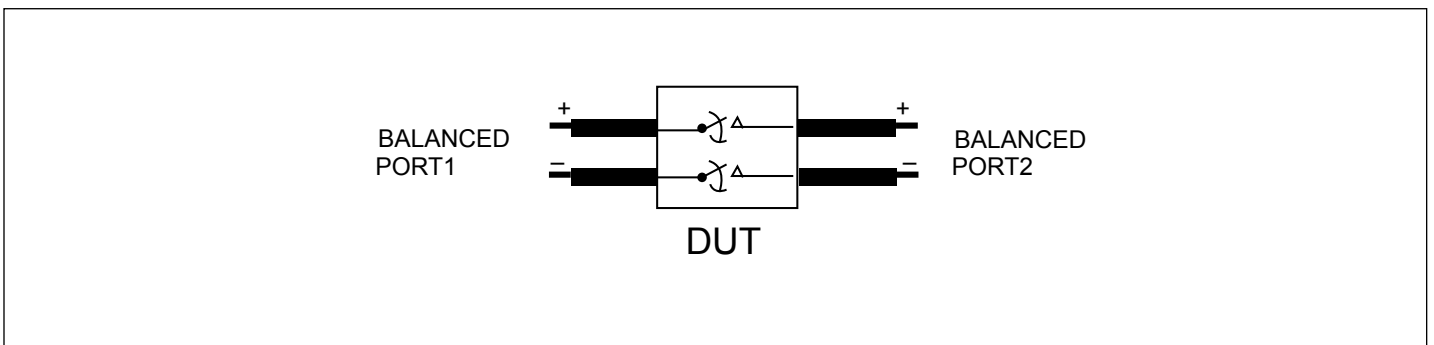


Fig 3. Differential Insertion Loss set up

PI3USB32212



Fig 4. Differential Crosstalk – Super Speed



Fig 5. Differential Off Isolation – Super Speed

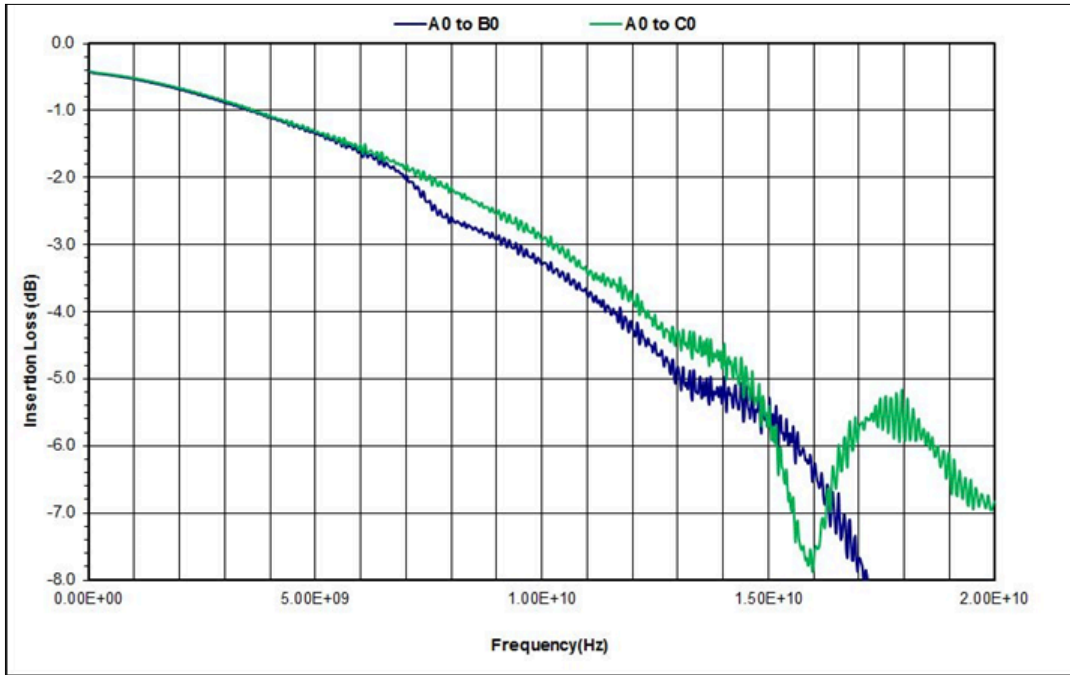


Fig 6. Differential Insertion Loss – Super Speed

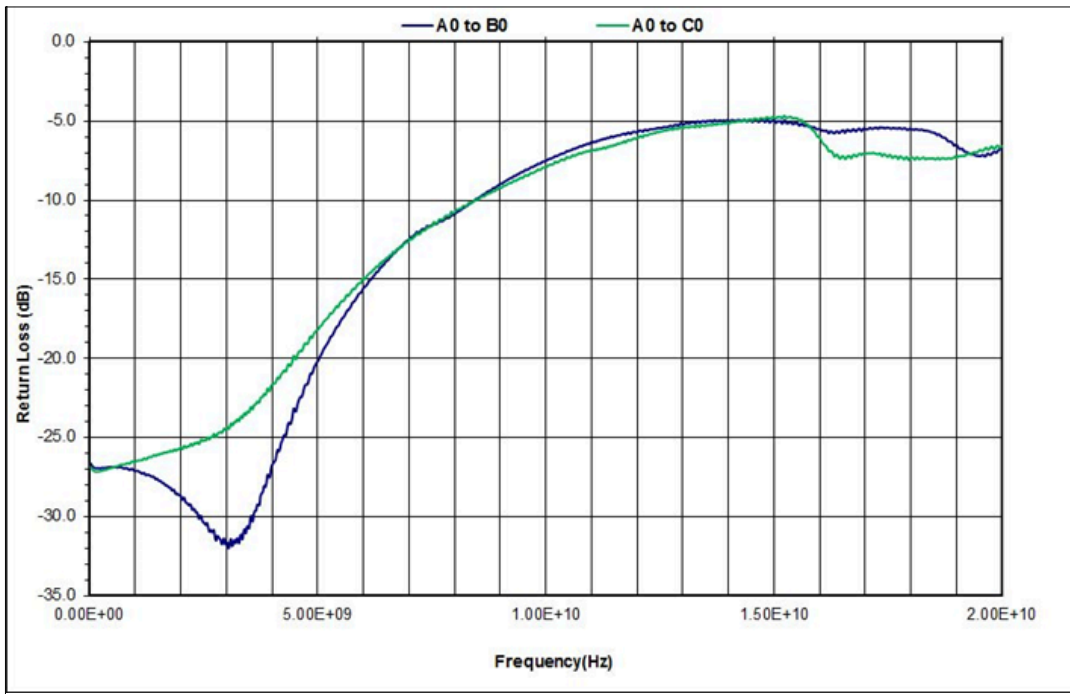


Fig 7. Differential Return Loss – Super Speed

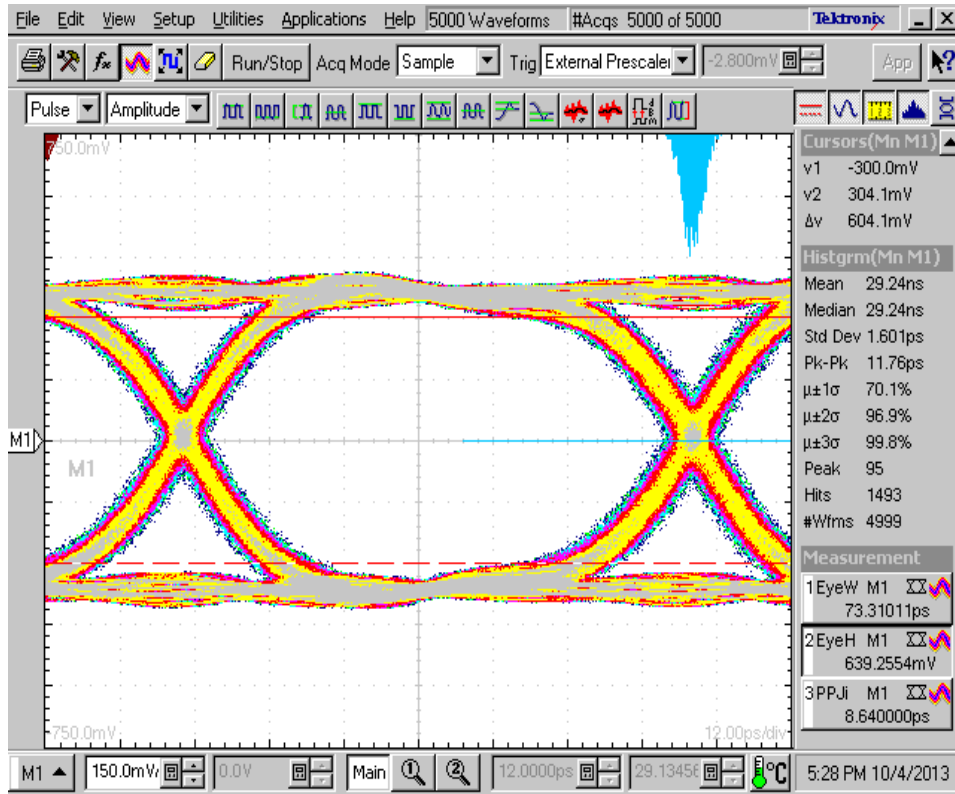


Fig 8. 12Gbps Eye without PI3USB32212

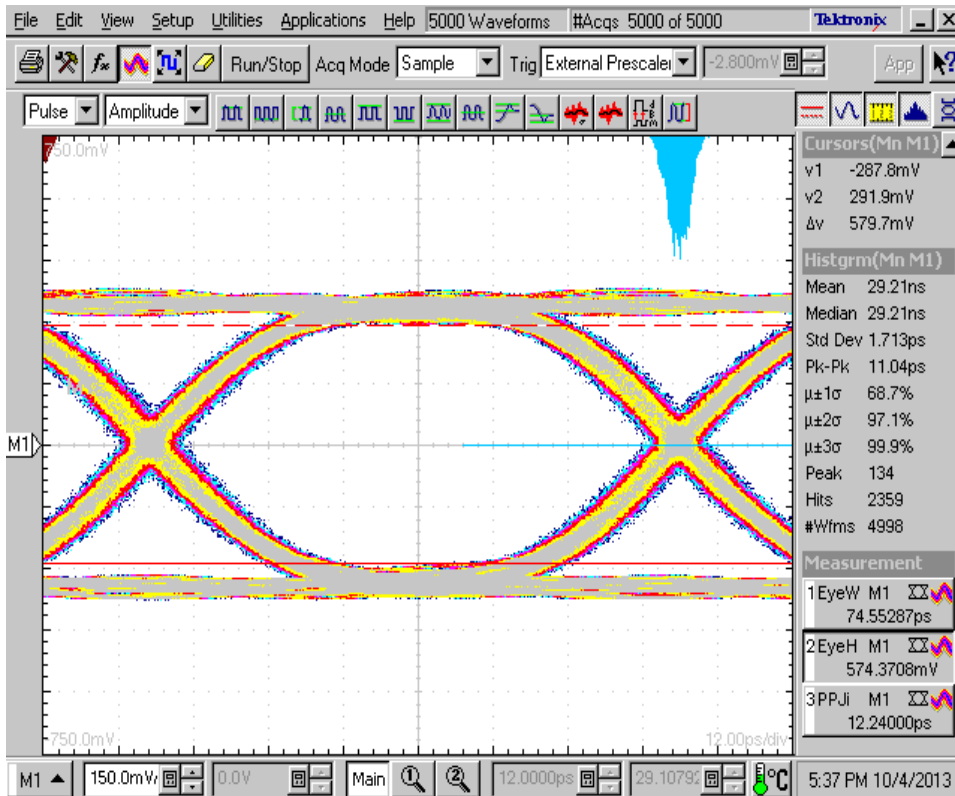


Fig 9. 12Gbps Eye with PI3USB32212

PI3USB32212

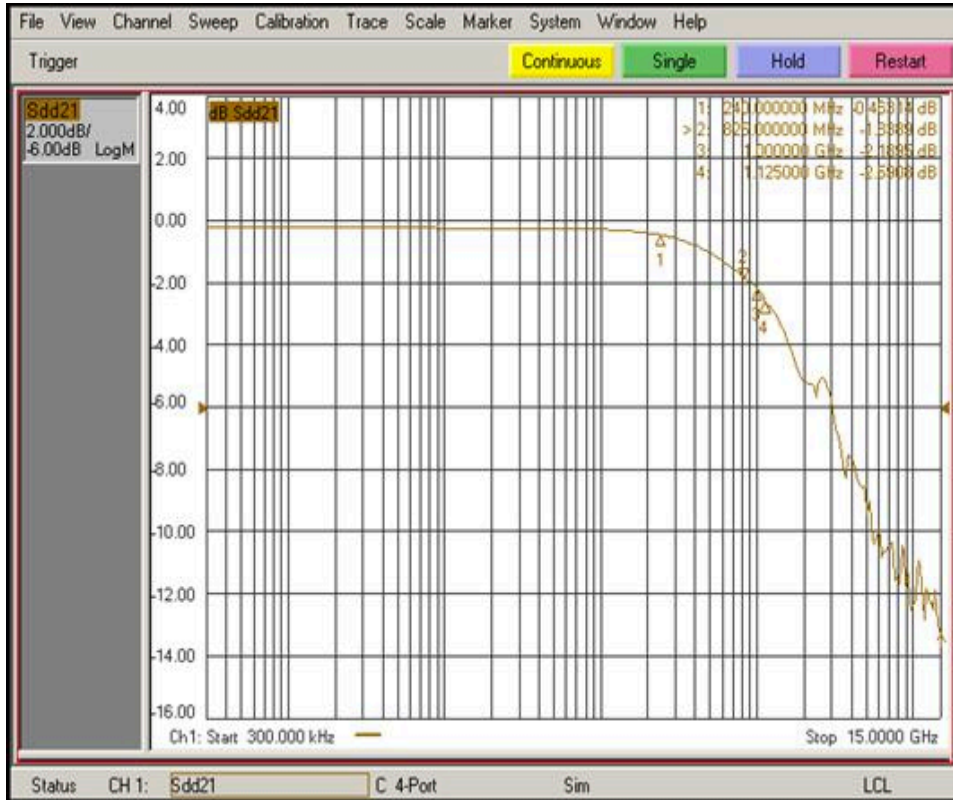
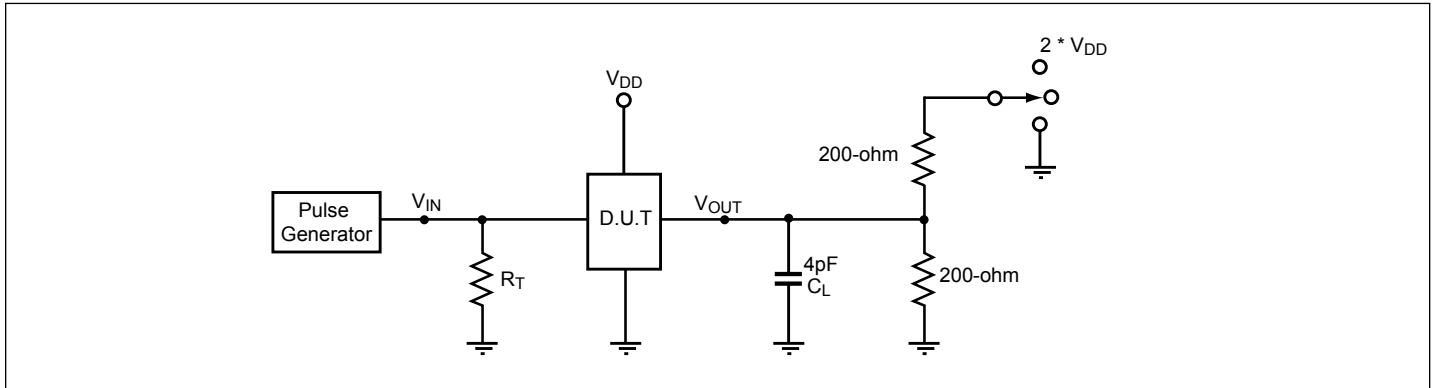


Fig 10. Differential Insertion loss, $V_{DD} = 3.3V$ – USB2 HS

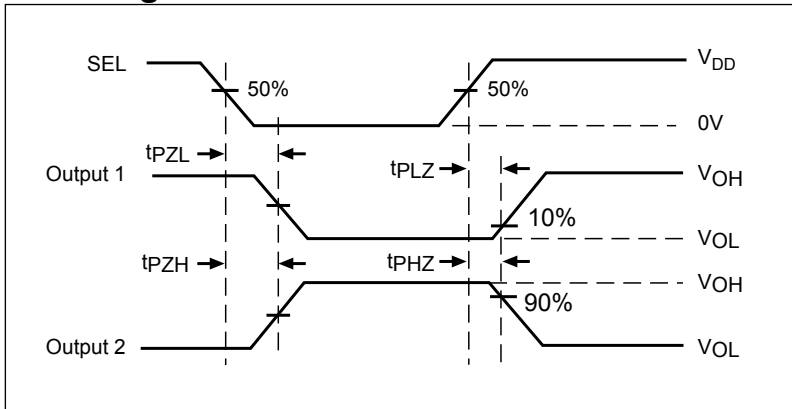
Test Circuit for Electrical Characteristics(1-5)



Notes:

1. C_L = Load capacitance: includes jig and probe capacitance.
2. R_T = Termination resistance: should be equal to Z_{OUT} of the Pulse Generator
3. Output 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
4. Output 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
5. All input impulses are supplied by generators having the following characteristics: $PRR \leq \text{MHz}$, $Z_O = 50\Omega$, $t_R \leq 2.5\text{ns}$, $t_F \leq 2.5\text{ns}$.
6. The outputs are measured one at a time with one transition per measurement.

Switching Waveforms

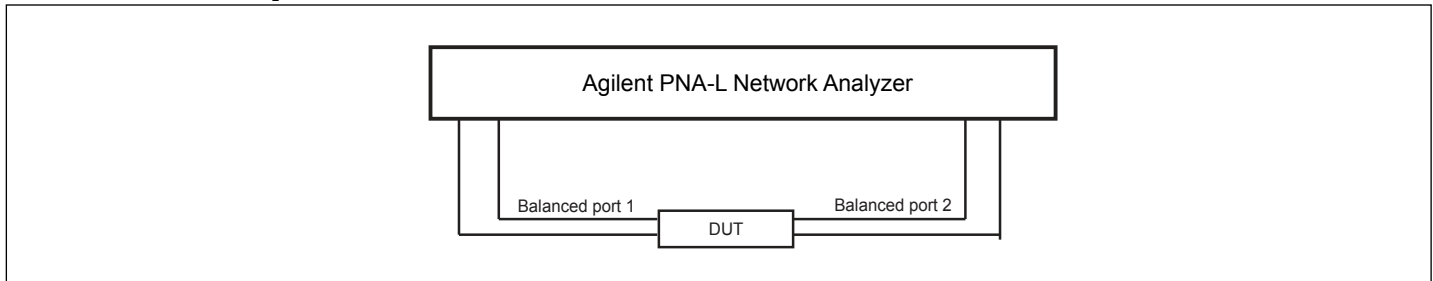


Voltage Waveforms Enable and Disable Times

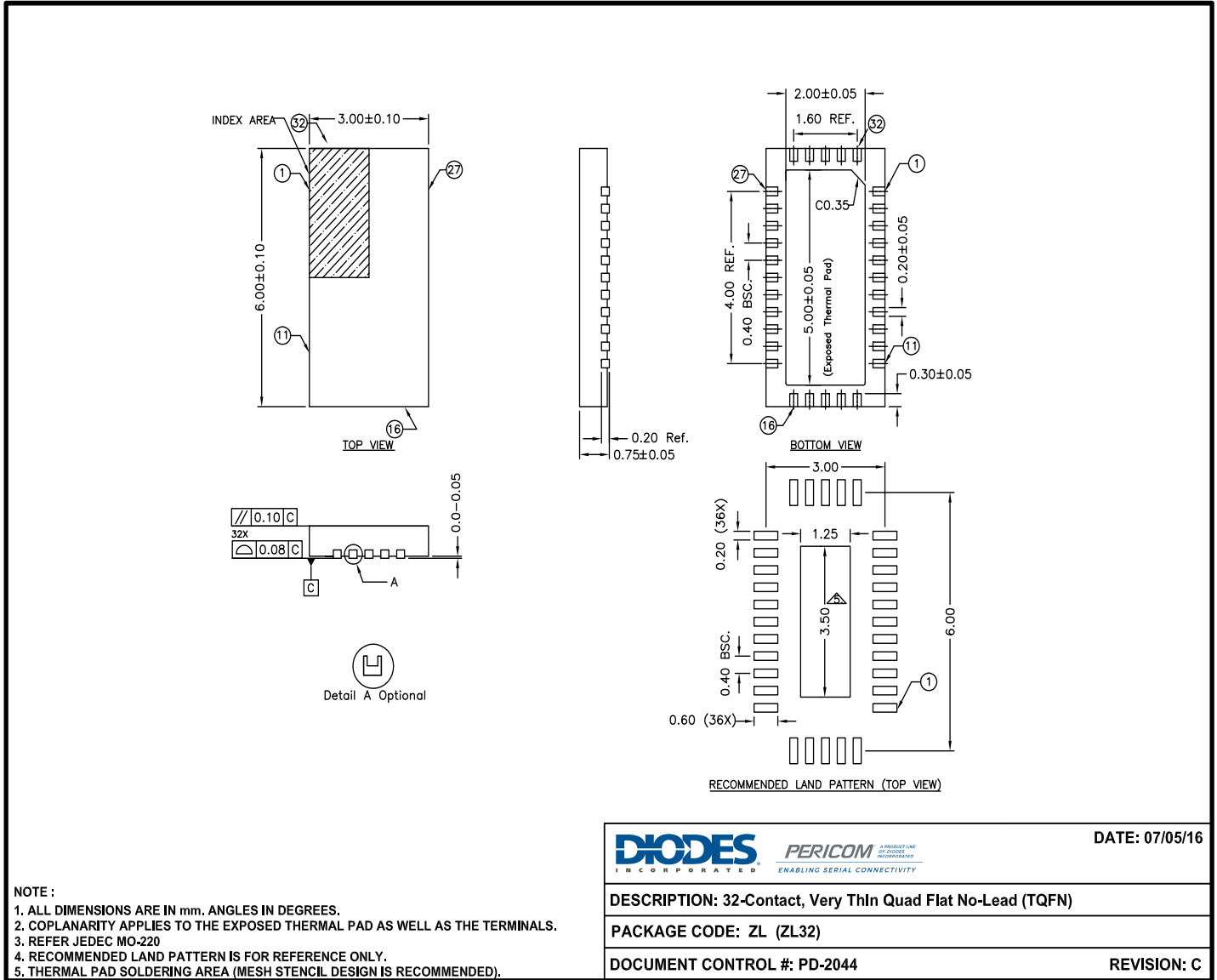
Switch Positions

| Test | Switch |
|--|--------------|
| t_{PLZ} , t_{PZL} (output on B-side) | $2 * V_{DD}$ |
| t_{PHZ} , t_{PHZ} (output on B-side) | GND |
| Prop Delay | Open |

Test Circuit for Dynamic Electrical Characteristics



Packaging Mechanical: 32-TQFN (ZL)



16-0142

For latest package info.

please check: <http://www.diodes.com/design/support/packaging/pericom-packaging/packaging-mechanicals-and-thermal-characteristics/>

Ordering Information

| Ordering Code | Package Code | Package Description |
|--------------------|--------------|--|
| PI3USB32212ZLEX | ZL | 32-contact, Very Thin Quad Flat No-Lead (TQFN) Copper Wire |
| PI3USB32212ZLEX+DA | ZL | 32-contact, Very Thin Quad Flat No-Lead (TQFN) Gold Wire |

Notes:

- Thermal characteristics can be found on the company web site at www.diodes.com/design/support/packaging/
- E = Pb-free and Green
- X suffix = Tape/Reel

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